Silicon N-channel IGBT 1700V F version

#### **FEATURES**

\* Soft switching behavior & low conduction loss :

Soft low-injection punch-through with

Advanced trench HiGT\* (\*High conductivity IGBT)

\* Low driving power:

Low input capacitance advanced trench gate.

\* Low noise recovery: Ultra soft fast recovery diode.

#### ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub>=25°C)

Item		Symbol	Unit	MBN3600E17F
Collector Emitter Voltage		V <sub>CES</sub>	V	1,700
Gate Emitter Voltage		$V_{GES}$	V	±20
Collector Current	DC	Ic	A	3,600
	1ms	I <sub>CRM</sub>	7 ^	7,200
Forward Current	DC	l <sub>F</sub>	A	3,600
	1ms	I <sub>FRM</sub>	7 ^	7,200
Junction Temperature		T <sub>vj op</sub>	°C	-50 ~ +150
Storage Temperature		T <sub>stg</sub>	°C	-55 ~ +125
Isolation Voltage		V <sub>ISO</sub>	V <sub>RMS</sub>	4,000(AC 1 minute)
Screw Torque	Terminals (M4/M8)	-	N⋅m	2/15 (1)
	Mounting (M6)	-	111-111	6 (2)

Notes: (1) Recommended Value 1.8±0.2/15<sup>+0</sup><sub>-3</sub>N·m (2) Recommended Value 5.5±0.5N·m

#### **ELECTRICAL CHARACTERISTICS**

Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions		
Collector Emitter Cut-Off Current		mA	-	-	10	V <sub>CE</sub> =1,700V, V <sub>GE</sub> =0V, T <sub>vj</sub> =25°C		
Collector Emitter Cut-On Current	I <sub>CES</sub>		-	35	150	V <sub>CE</sub> =1,700V, V <sub>GE</sub> =0V, T <sub>vi</sub> =150°C		
Gate Emitter Leakage Current	I <sub>GES</sub>	nA	-500	-	+500	$V_{GE}=\pm 20V$ , $V_{CE}=0V$ , $T_{vj}=25$ °C		
Collector Emitter Saturation Voltage	V <sub>CEsat</sub>	V	-	2.4	2.8	I <sub>C</sub> =3,600A, V <sub>GE</sub> =15V, T <sub>vj</sub> =150°C		
Gate Emitter Threshold Voltage	V <sub>GE(th)</sub>	V	4.1	5.5	7.1	V <sub>CE</sub> =10V, I <sub>C</sub> =360mA, T <sub>Vj</sub> =25°C		
Input Capacitance	Cies	nF	-	177	-	$V_{CE}=10V$ , $V_{GE}=0V$ , $f=100kHz$ , $T_{vj}=25$ °C		
Internal Gate Resistance	R <sub>G(int)</sub>	Ω	-	1.3	-	V <sub>CE</sub> =10V, V <sub>GE</sub> =0V, f=100kHz, T <sub>vi</sub> =25°C		
Turn On Delay Time	t <sub>d(on)</sub>		-	1.05	2.0	V <sub>CC</sub> =900V, I <sub>C</sub> =3,600A		
Rise Time	t <sub>r</sub>		-	0.35	0.8	L <sub>S</sub> =55nH		
Turn Off Delay Time	t <sub>d(off)</sub>	μS	-	1.7	3.4	$R_{G}(\text{on/off})=3.3/3.3\Omega$ (3)		
Fall Time	t <sub>f</sub>		-	1.6	3.2	$V_{GE}=\pm 15V, T_{vj}=150^{\circ}C$		
Peak Forward Voltage Drop	V <sub>F</sub>	V	-	2.25	2.7	$I_F=3,600A, V_{GE}=0V, T_{vj}=150^{\circ}C$		
Reverse Recovery Time	t <sub>rr</sub>	μS	-	0.8	1.6	V <sub>CC</sub> =900V, I <sub>F</sub> =3,600A, L <sub>S</sub> =55nH		
						T <sub>vj</sub> =150°C		
Turn On Loss	Eon	J/P	-	1.4	-	V <sub>CC</sub> =900V, I <sub>C</sub> =3,600A, L <sub>S</sub> =55nH		
Turn Off Loss	E <sub>off</sub>	J/P	-	3.0	-	$R_{G}(\text{on/off})=3.3/3.3\Omega$ (3)		
Reverse Recovery Loss	Err	J/P	-	1.15	-	$V_{GE}=\pm 15V, T_{vj}=150^{\circ}C$		
Short Circuit Pulse Width	4	μS	10	-	-	V <sub>CC</sub> =1,100V,Ls=55nH		
Short Circuit Fuise Width	t <sub>sc</sub>					$R_G(\text{on/off})=3.3/15\Omega, V_{GE}=\pm 15V, T_{vj}=150^{\circ}C$		
Stray inductance module	L <sub>SCE</sub>	nΗ	-	8	-			
Thermal Impedance IGBT	R <sub>th(j-c)</sub>	K/W	-	-	0.0072	Junction to case		
FWD	R <sub>th(j-c)</sub>		-	-	0.011	Juniculon to case		
Contact Thermal Impedance	R <sub>th(c-f)</sub>	K/W	-	0.005	-	Case to fin		

Notes: (3)  $R_G$  value is a test condition value for evaluation, not recommended value. Please, determine the suitable  $R_G$  value by measuring switching behaviors.

<sup>\*</sup> ELECTRICAL CHARACTERISTIC items shown in above table are according to IEC 60747-2 and IEC 60747-9.



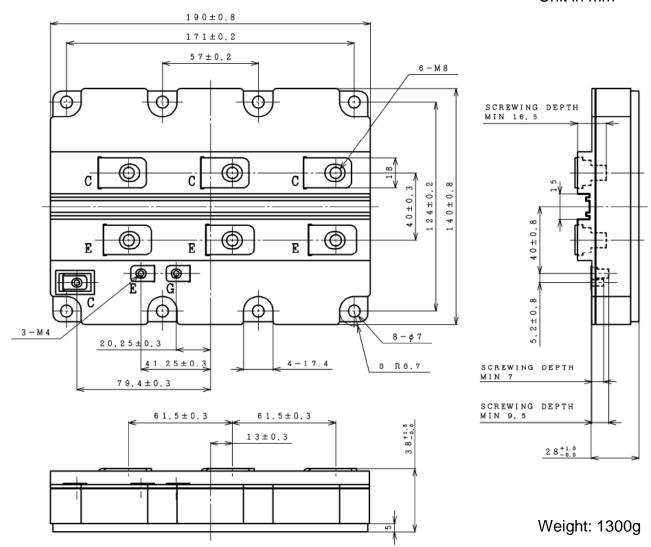
<sup>\*</sup> Please contact our representatives at order.

<sup>\*</sup> For improvement, specifications are subject to change without notice.

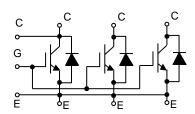
<sup>\*</sup> For actual application, please confirm this spec sheet is the newest revision.

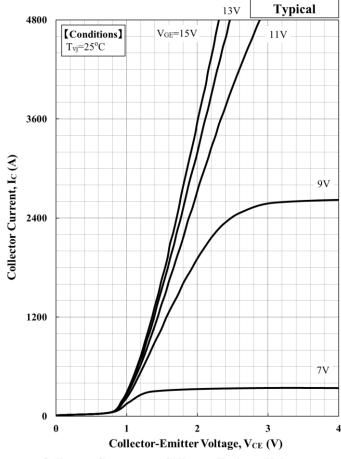
#### **OUTLINE DRAWING**

Unit in mm

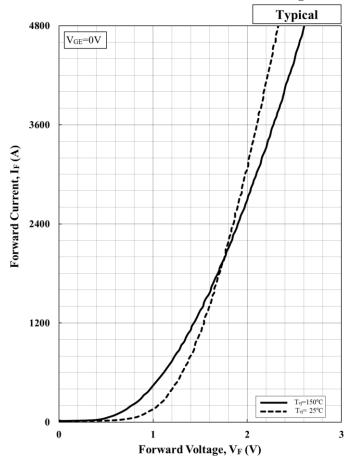


#### **CIRCUIT DIAGRAM**

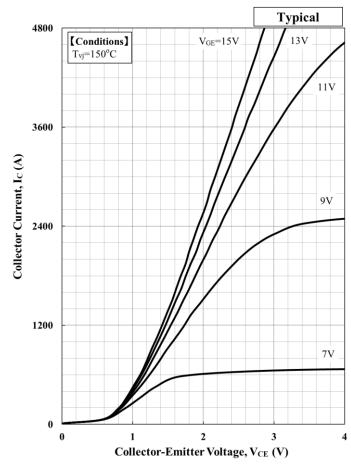




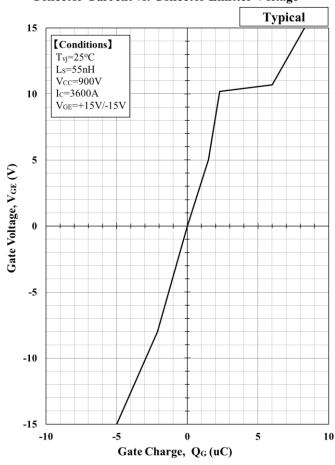
Collector Current vs. Collector Emitter Voltage



Forward Voltage of free-wheeling diode

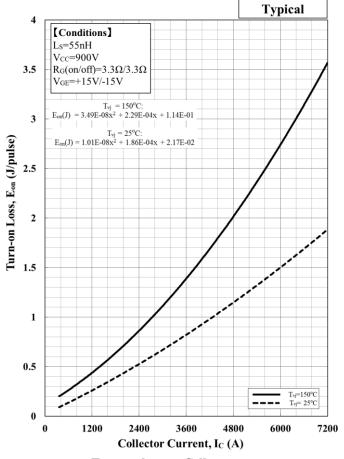


Collector Current vs. Collector Emitter Voltage

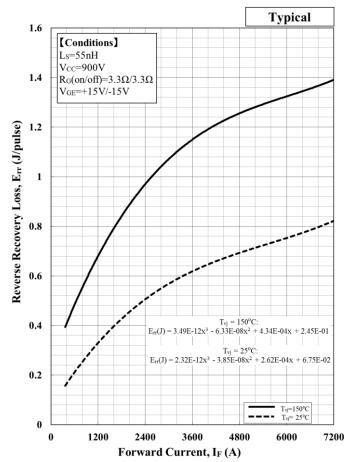


 $m V_{GE}$ - $m Q_G$  curve

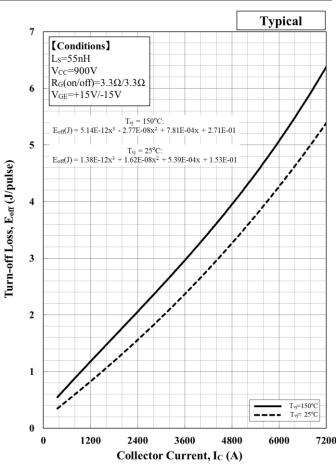
HITACHI Inspire the Next



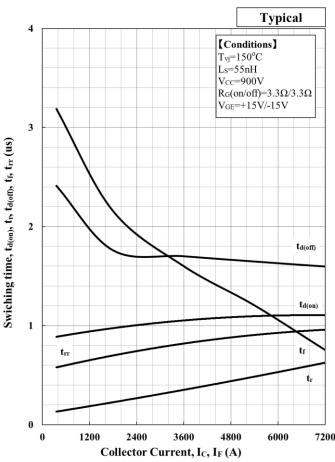
Turn-on loss vs. Collector current



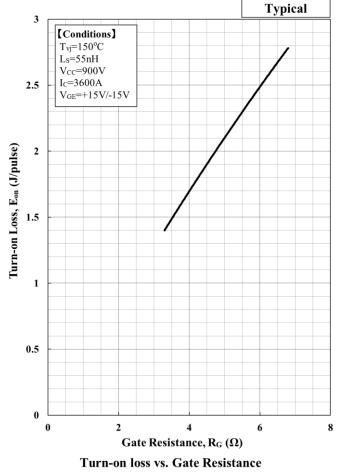
Recovery loss vs. Forward current

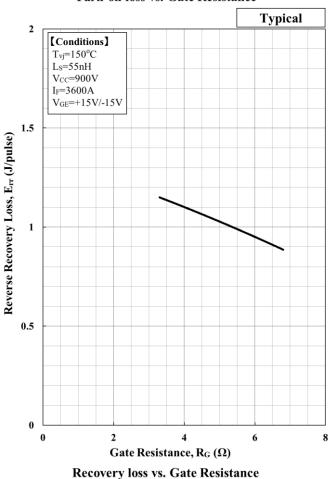


Turn-off loss vs. Collector current



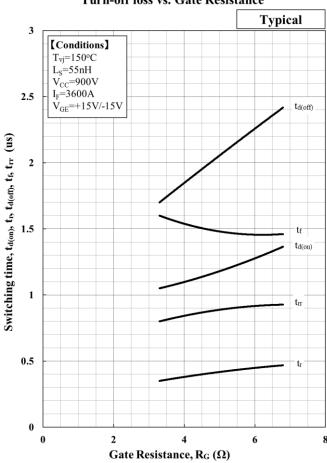
Switching time vs. Collector Current
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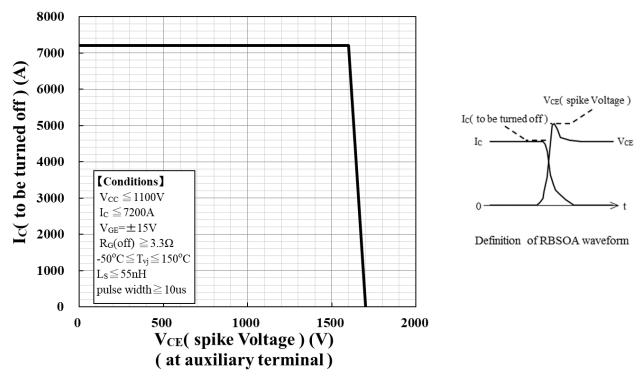
| Typical | Typ

Turn-off loss vs. Gate Resistance

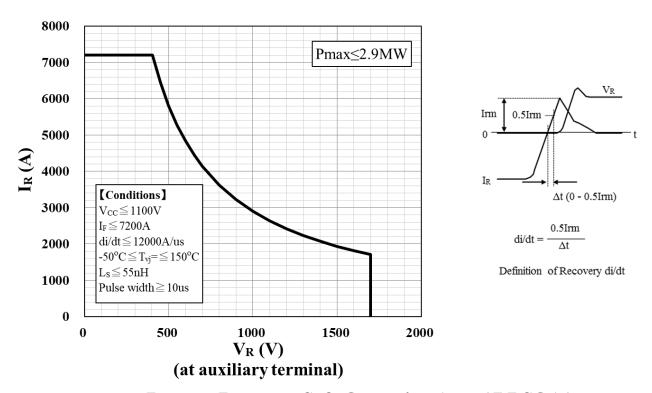


Switching time vs. Gate Resistance

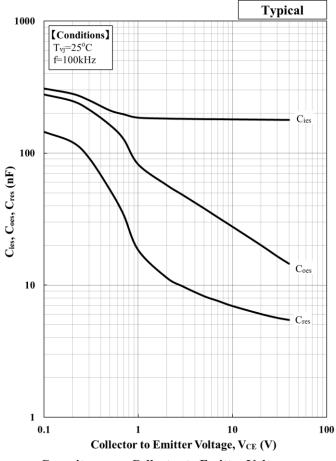


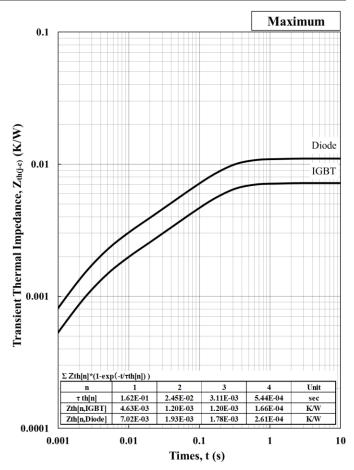


### Reverse Bias Safe Operation Area (RBSOA)



Reverse Recovery Safe Operation Area (RRSOA)





Capacitance vs. Collector to Emitter Voltage

**Transient Thermal Ipedance Curve** 

### **Material declaration**

Please note the following materials are contained in the product, in order to keep characteristic and reliability level.

Material	Contained part
Lead (Pb) and its compounds	Solder



### HITACHI POWER SEMICONDUCTORS

### Notices

- 1. Since mishandling of semiconductor devices may cause malfunctions, please be sure to read "Precautions for Safe Use and Notices" in the individual brochure before use.
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